

Modeling the power-reliability tradeoff in on-chip networks

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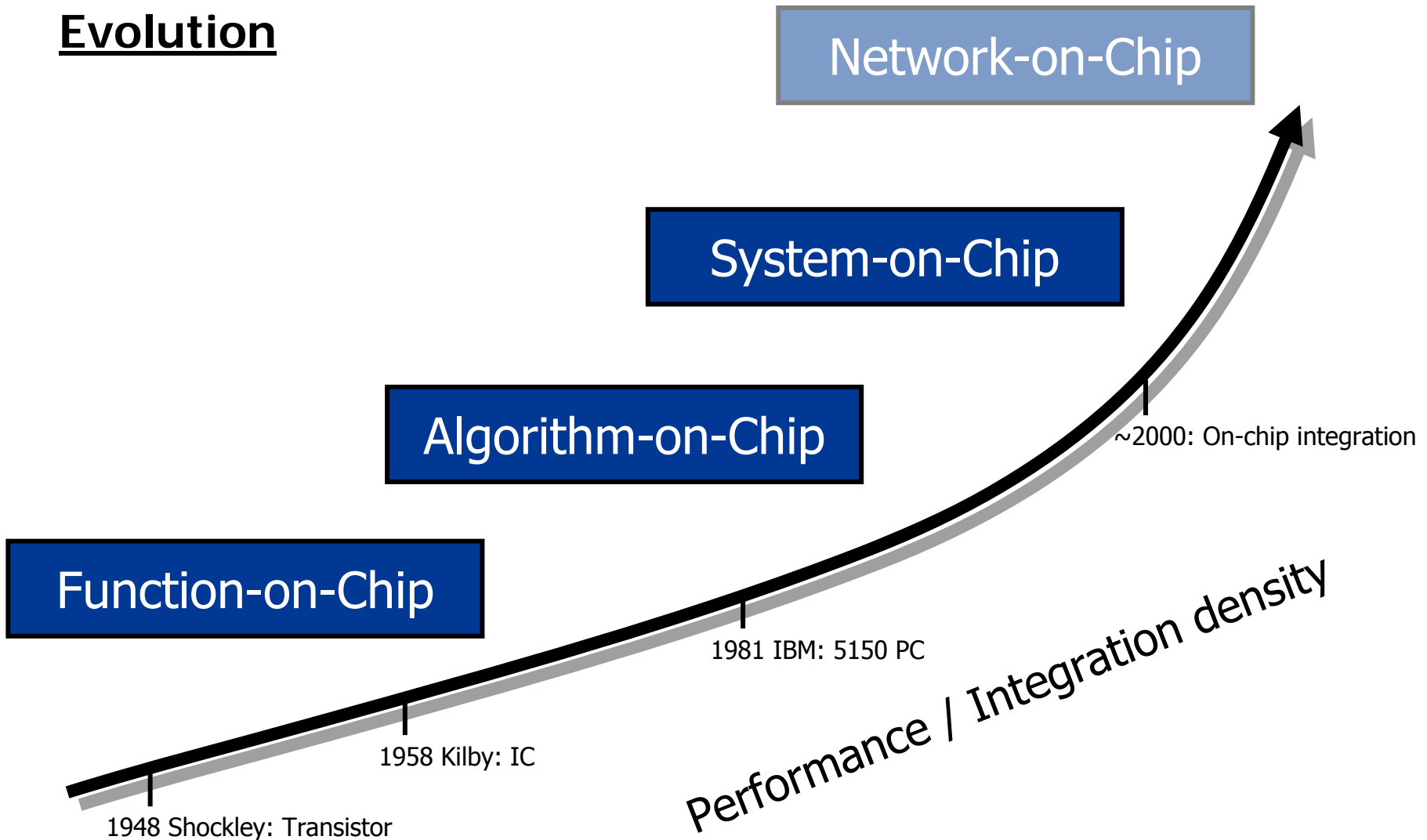


Outline

- Introduction
 - System design
 - Technology issues
- Approach
 - Analytical models
 - Simulation
- Results
- Summary

System design

Evolution

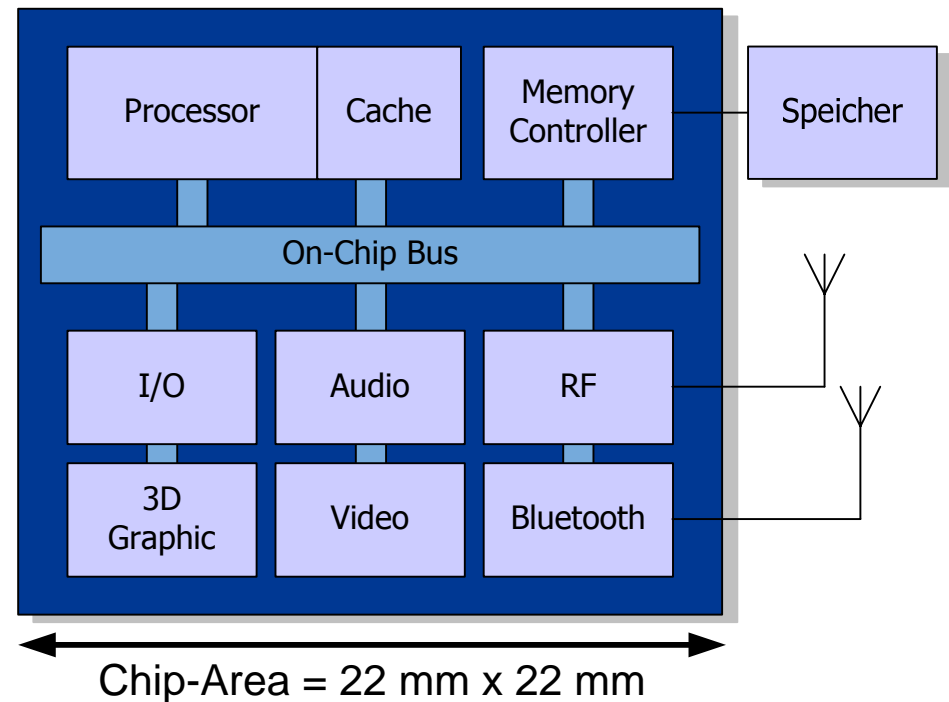


System design

Bus-based system design

→ Shared communication medium

- Connected problems:
 - Memory-Bottleneck
 - Design-Productivity-Gap
 - Synchronous design

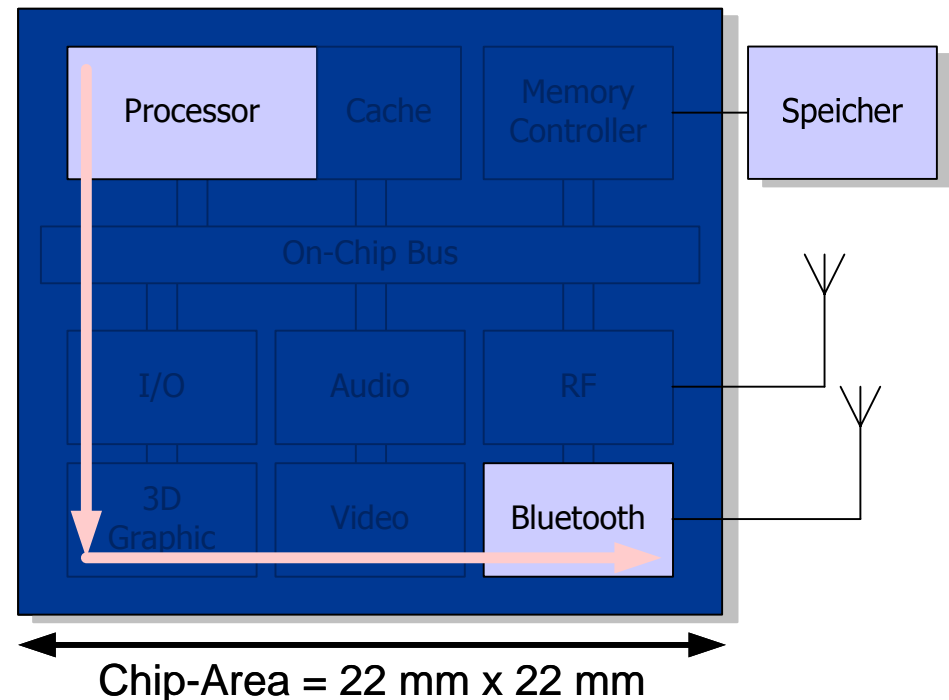


System design

Bus-based system design

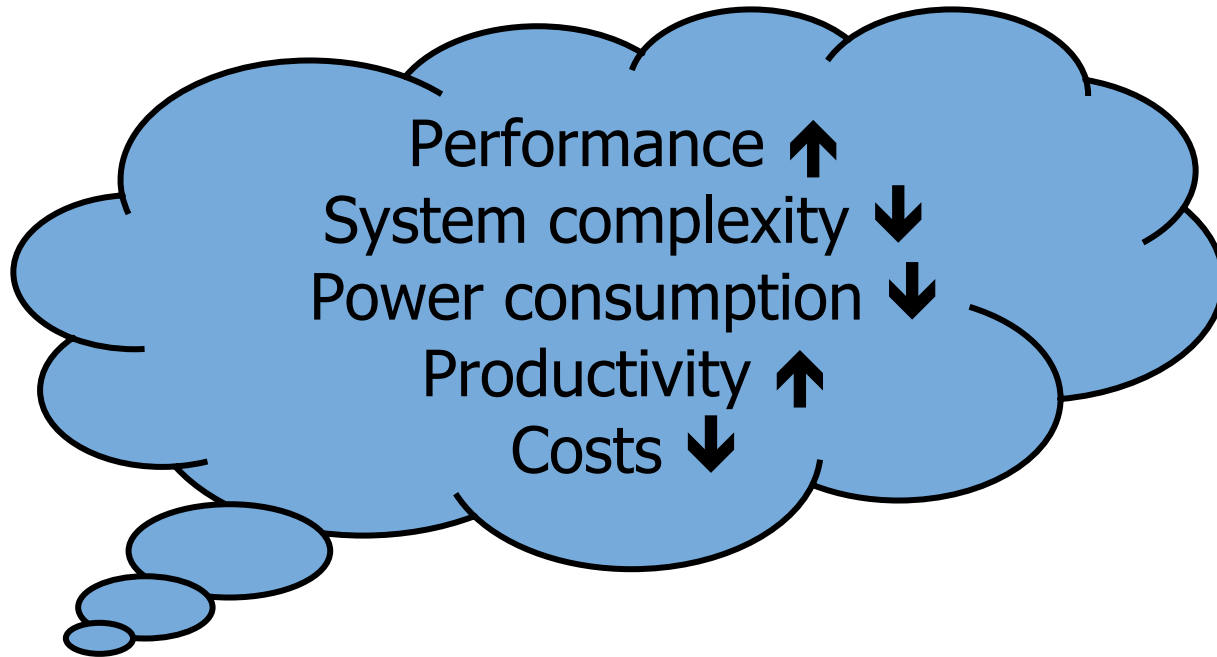
→ Shared communication medium

- Connected problems:
 - Memory-Bottleneck
 - Design-Productivity-Gap
 - Synchronous design
- Worsening the situation:
 - Chip-Size
 - Interconnects
 - Integration density
 - Parameter variability
 - ... and many more



System design

Wish list



[Intel]

“ ... multi-core processors are another [...] 10x factor in terms of performance ... ”

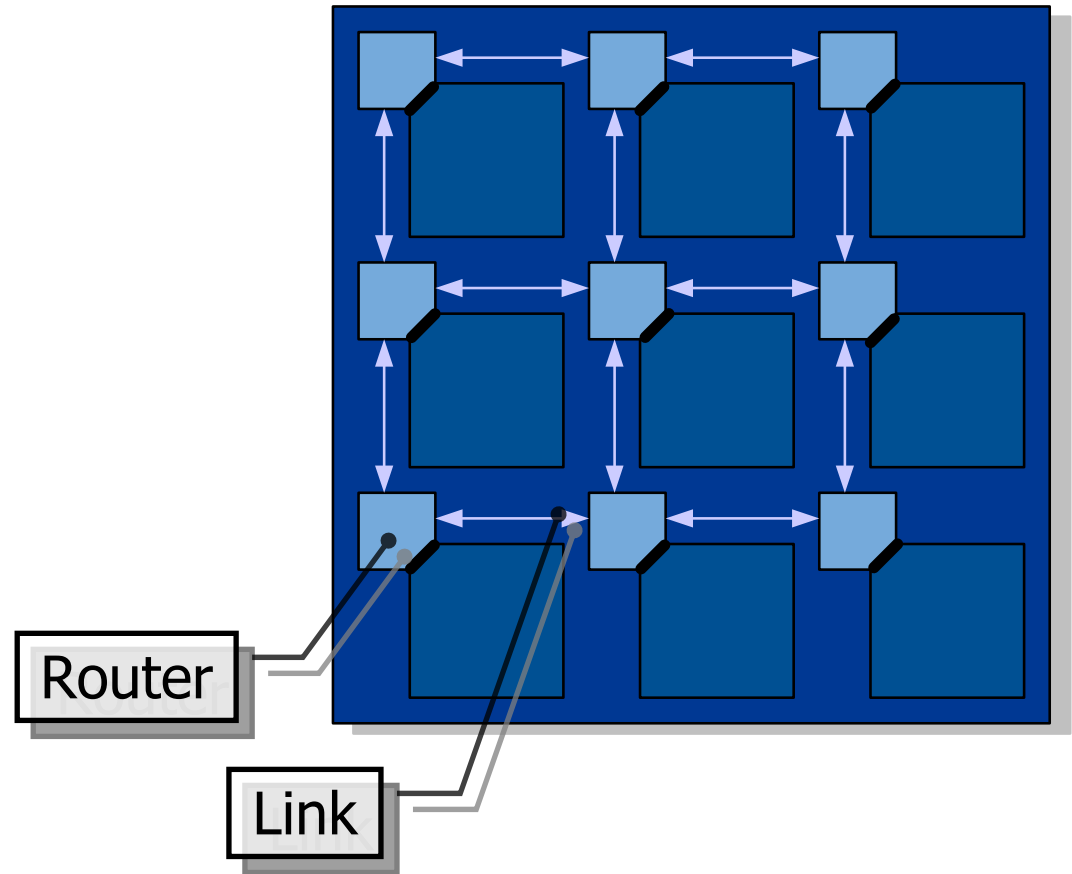
Paul Otellini, Intel President
IDF, September 2004

System design

Network-on-Chip

Promising properties:

- Parallelism
- Modularity



System design

Network-on-Chip

Promising properties:

- Parallelism
- Modularity

Level of abstraction:



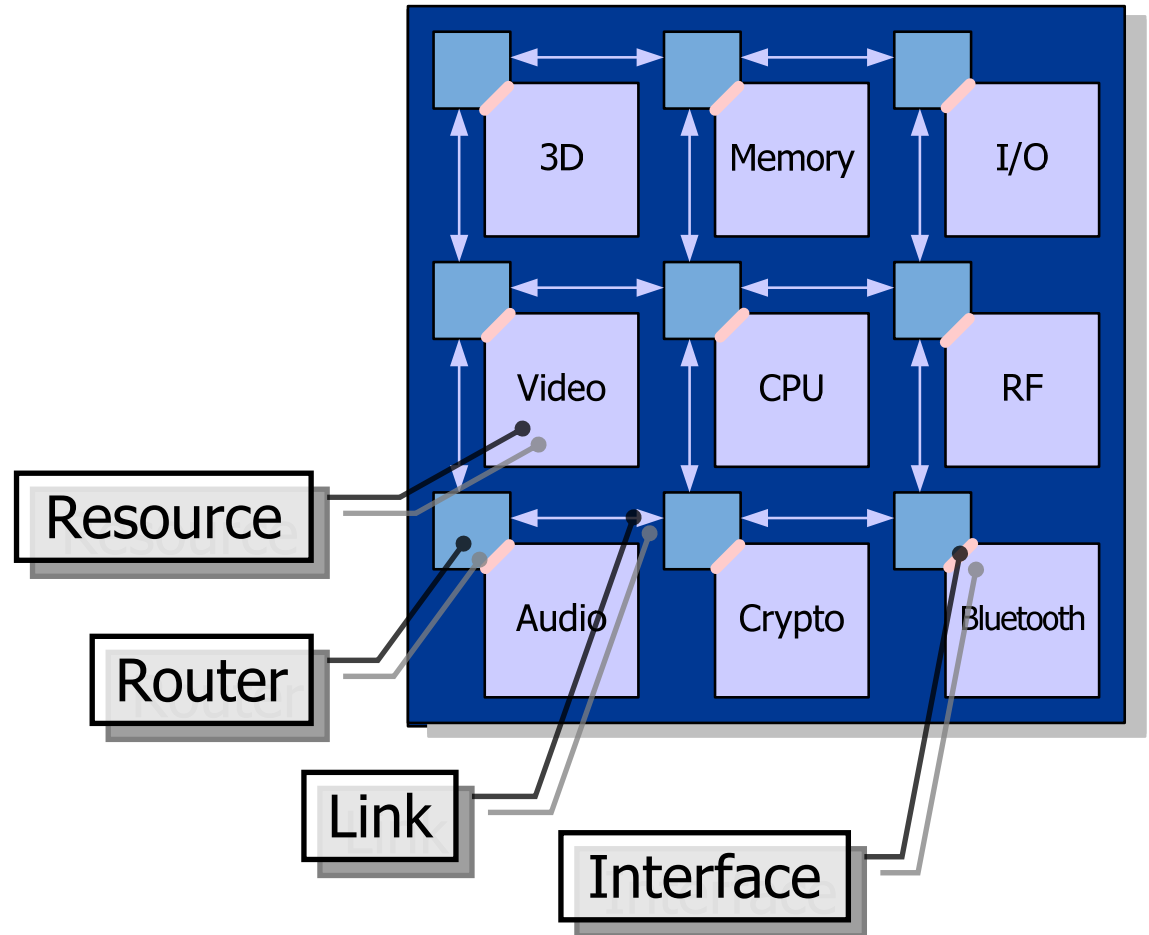
Modules
Logic-Gates
Transistors
Polygons

Change of Paradigms:

Computation



Communication



Technology issues

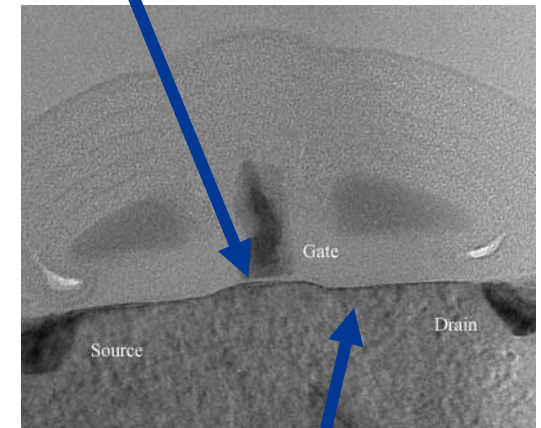
Technology scenario 2010

- Technology node 45 nm
- Chip size 620 mm²
- Transistor count 4424 Mio.
- Physical gate length ~20 nm
- Metal layers 12-16
- Frequency (global-local) 2-12 GHz
- Total wire length ~2.2 km/cm²
 - For M1-M6, 33% usage

[ITRS, 2003 and 2005]

- Approximate size of a resource
 - Rent's rule
 - Reachable die area with clock signal
 - Acceptable power trade-off

<10 Ångström gate
oxide thickness



[Intel, 2001]

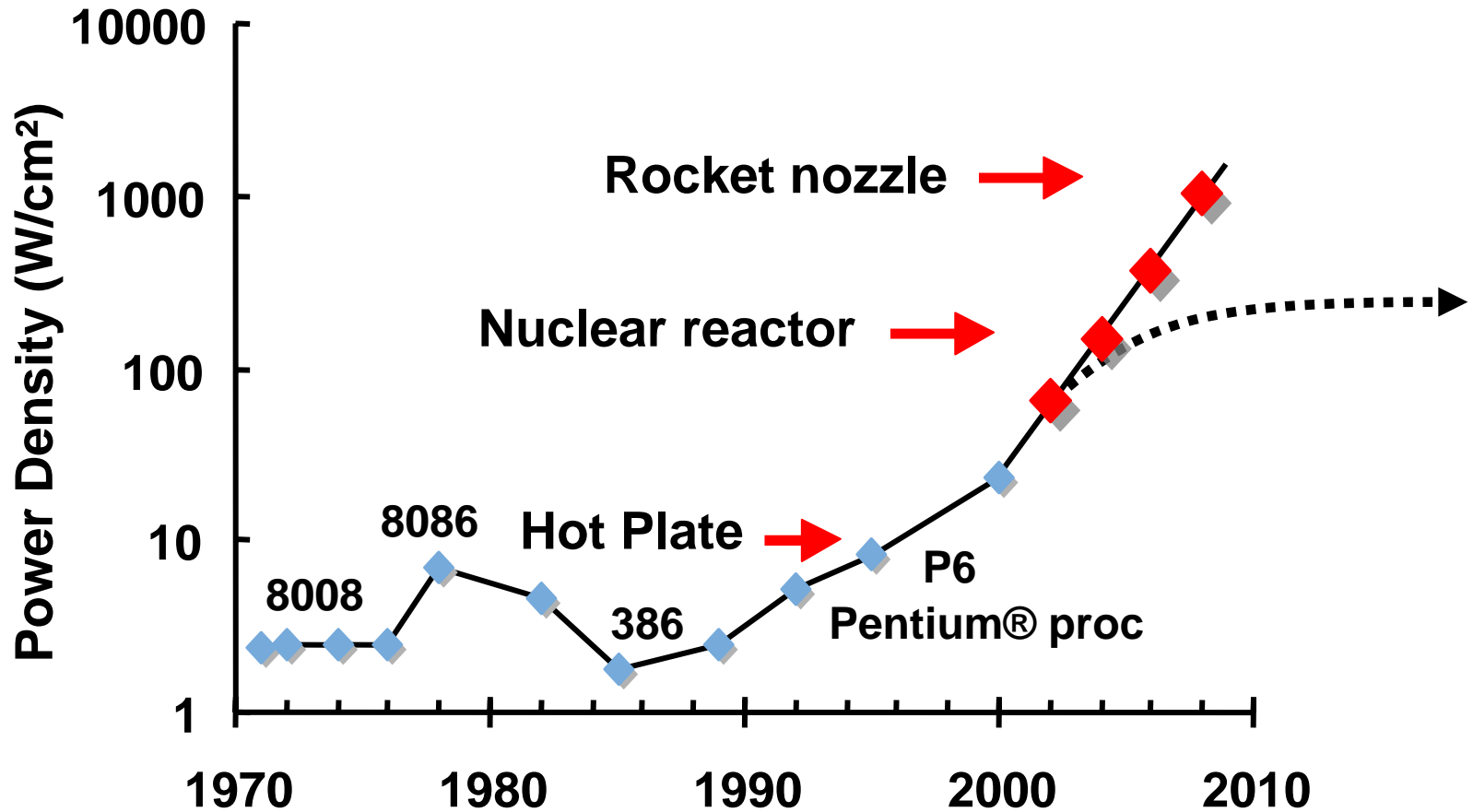
<100 dopant atoms



~85 resources

Technology issues

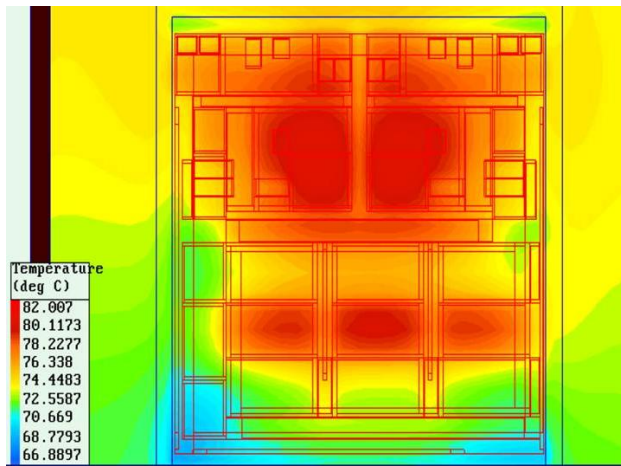
Power density



[Borkar]

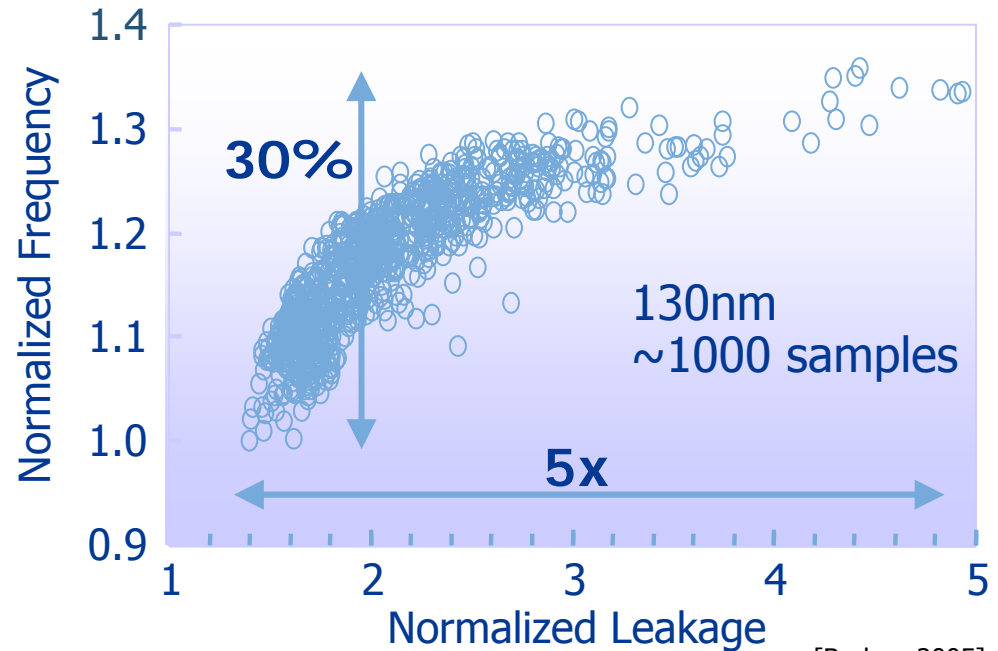
Technology issues

Parameter variability



Power4 Server Chip

[Devgan, 2003]



[Borkar, 2005]

L (nm)	250	180	130	90	65	45
Vt (mV)	450	400	330	300	280	200
σ -Vt (mV)	21	23	27	28	30	32
σ -Vt/Vt	4.7%	5.8%	8.2%	9.3%	10.7%	16%

[ITRS, 2003]

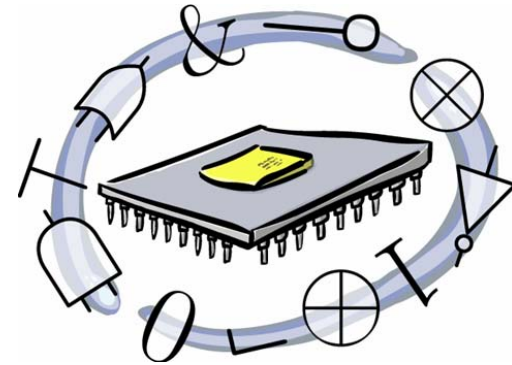


Parameter variability dramatically increasing

Approach

Related work

- Prototyping, Test-Chips
 - Star topology for multimedia applications [Lee, 2003]
 - 4x4 mesh network with traffic generators [Mullins, 2006]
- Parametrizable VHDL-model ported to FPGA [Zeferino, 2004]
- Emulation framework on an FPGA [Genko, 2005]
- High-level VHDL [Sigüenza, 2002]
- SystemC approach and design flow [Jalabert, 2004]
- Event-based C++ Simulator [Wiklund, 2004]



Approach

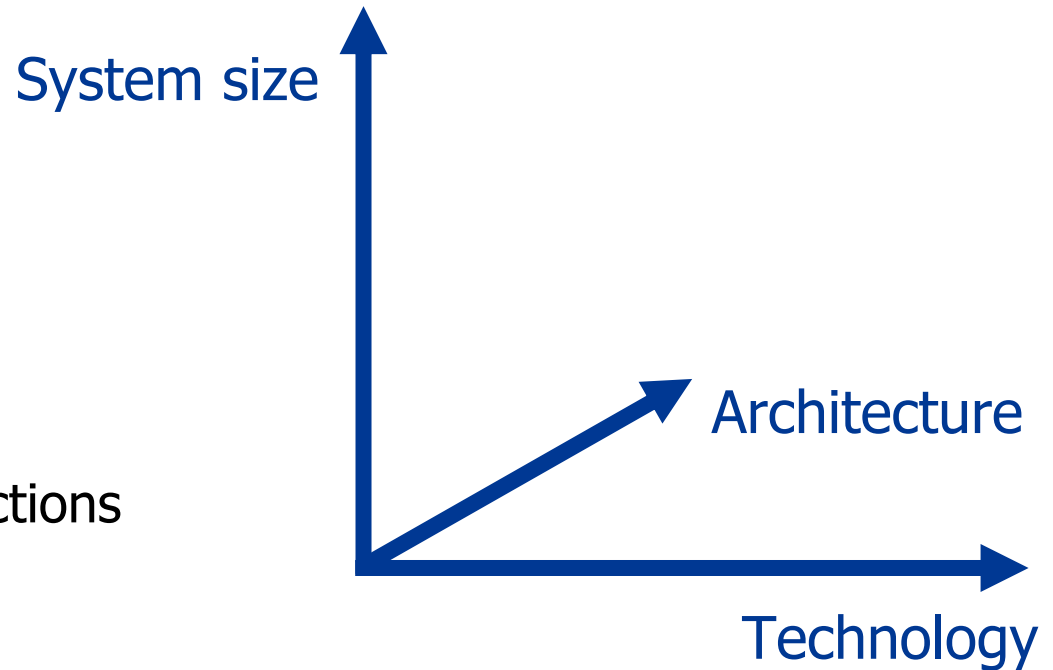
Design space exploration

1) Analytical models

- Fast evaluation
- Inaccurate Predictions

2) Simulation

- Computation and time intensive
- Accurate results



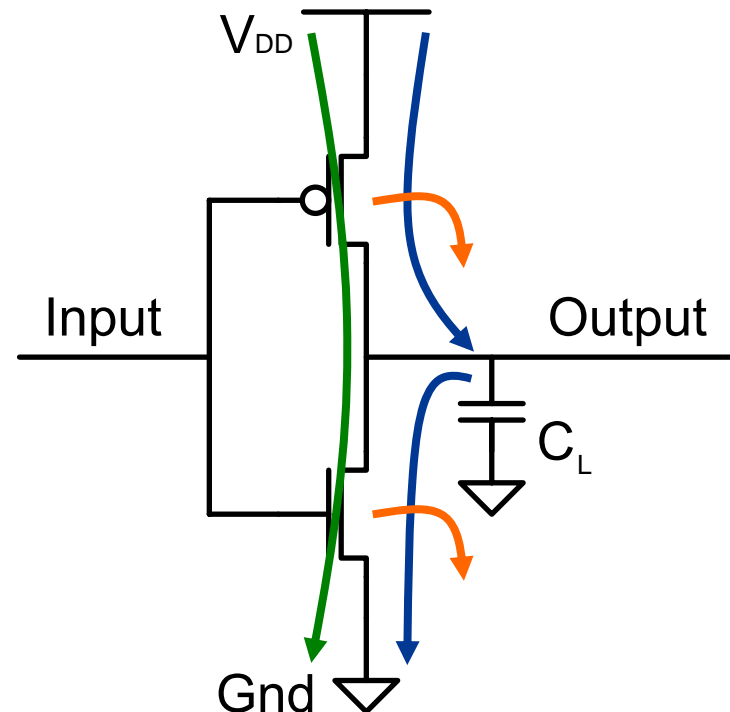
Analytical models

Power equation

$$P_{\text{total}} = \underbrace{\alpha C_L V_{\text{DD}}^2 f}_{\text{Dynamic}} + \underbrace{t_{\text{SC}} V_{\text{DD}} I_{\text{peak}} f}_{\text{Short-Circuit}} + \underbrace{V_{\text{DD}} I_{\text{leakage}}}_{\text{Leakage}}$$

E.g. Inverter
Output = $\overline{\text{Input}}$

- Glitches, Spikes, Hazards:
 - Due to race conditions of signals
 - Hard to predict
 - Mostly empirical assessment
- Static power due to design style



Analytical models

Reliability

Process

Random
Systematic
Parametric

Within-die
Die-to-die
Wafer-to-Wafer

Power supply
Ambient Temperature
Cooling

Environment

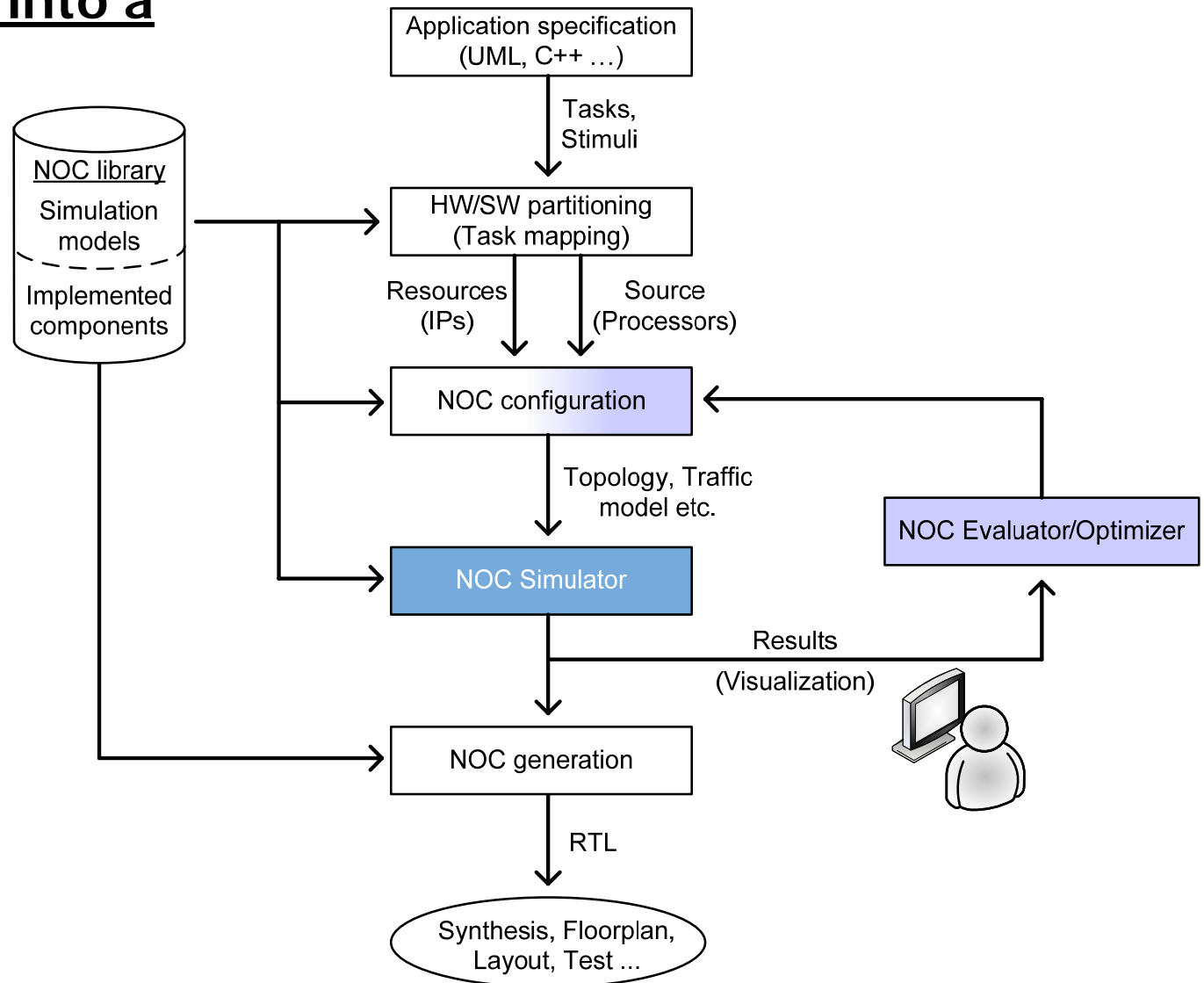
Time

Device degradation
Electromigration
Mechanical stress
Thermal stress

Crosstalk
EMI
 α -particles

Simulator

Integration into a design flow

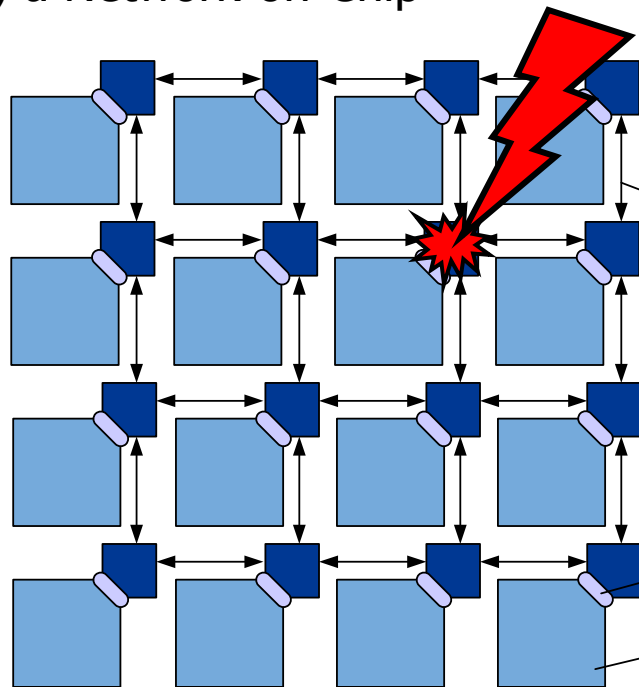


Results

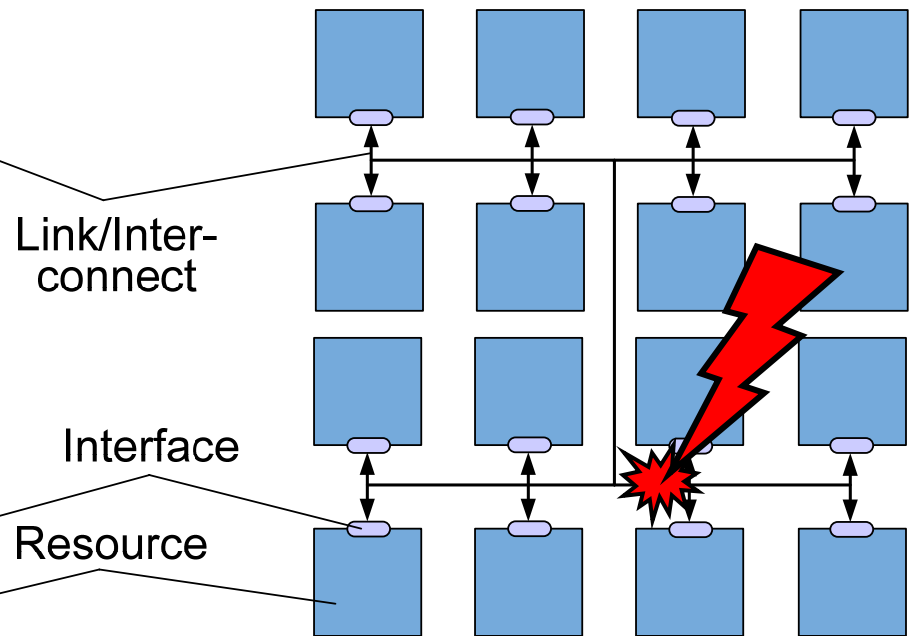
Scenario

Simple example of 16 resources/IPs in a regular 4x4 mesh interconnected with

a) a Network-on-Chip

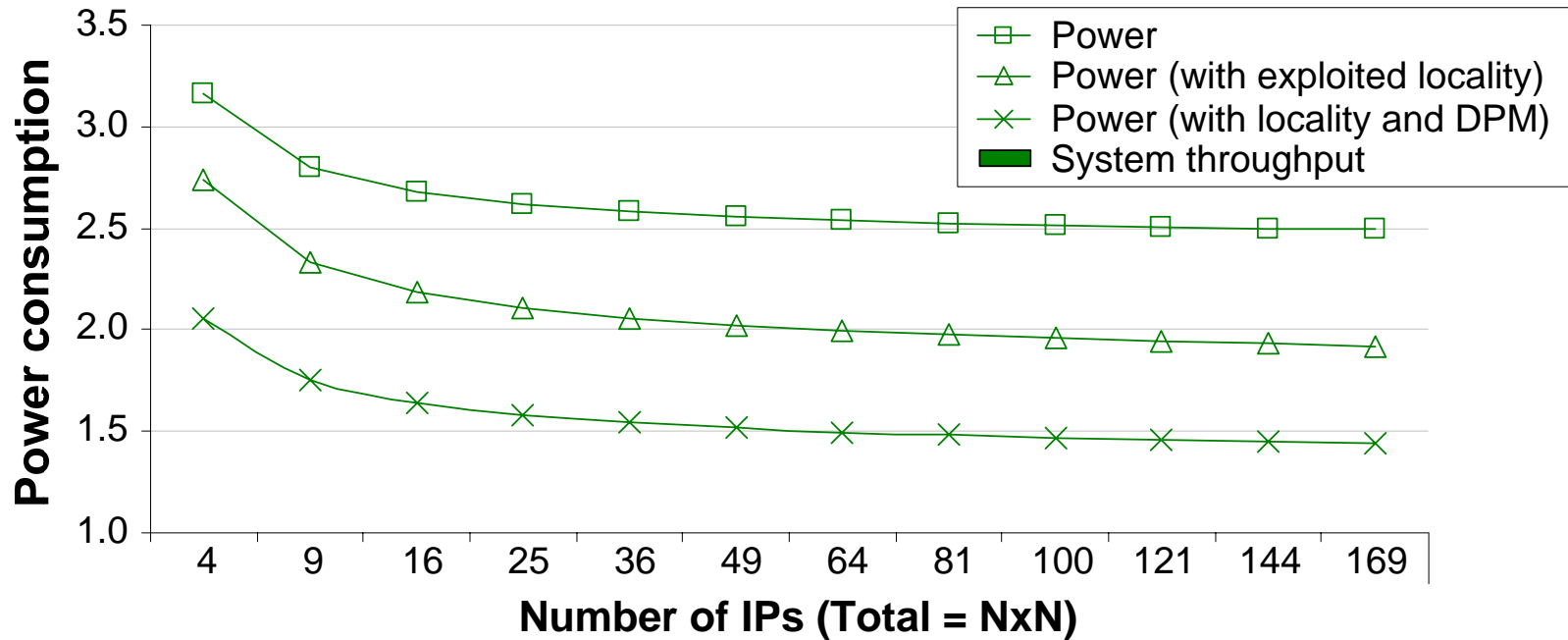


b) a single shared Bus



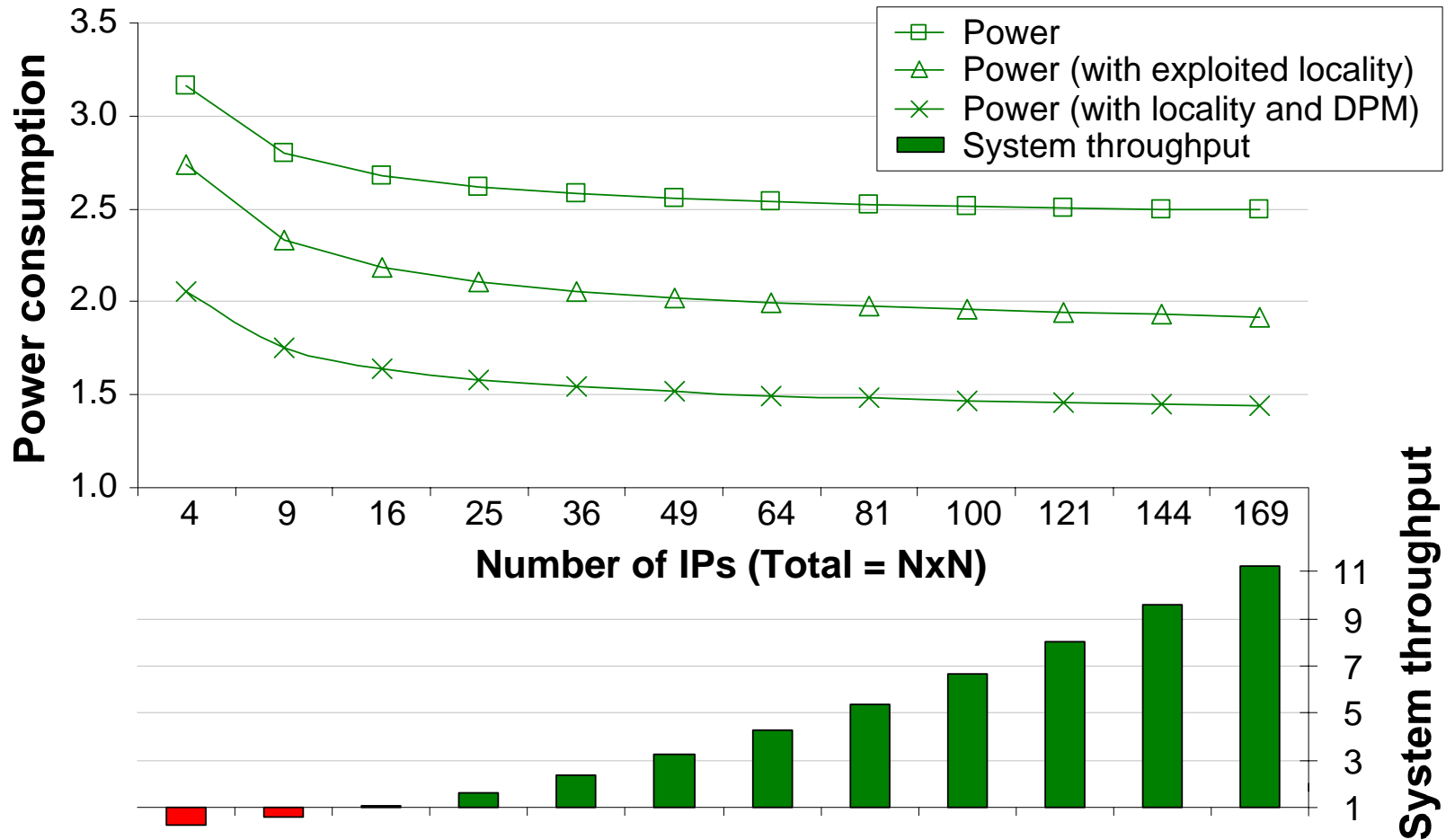
Results

Power and throughput



Results

Power and throughput

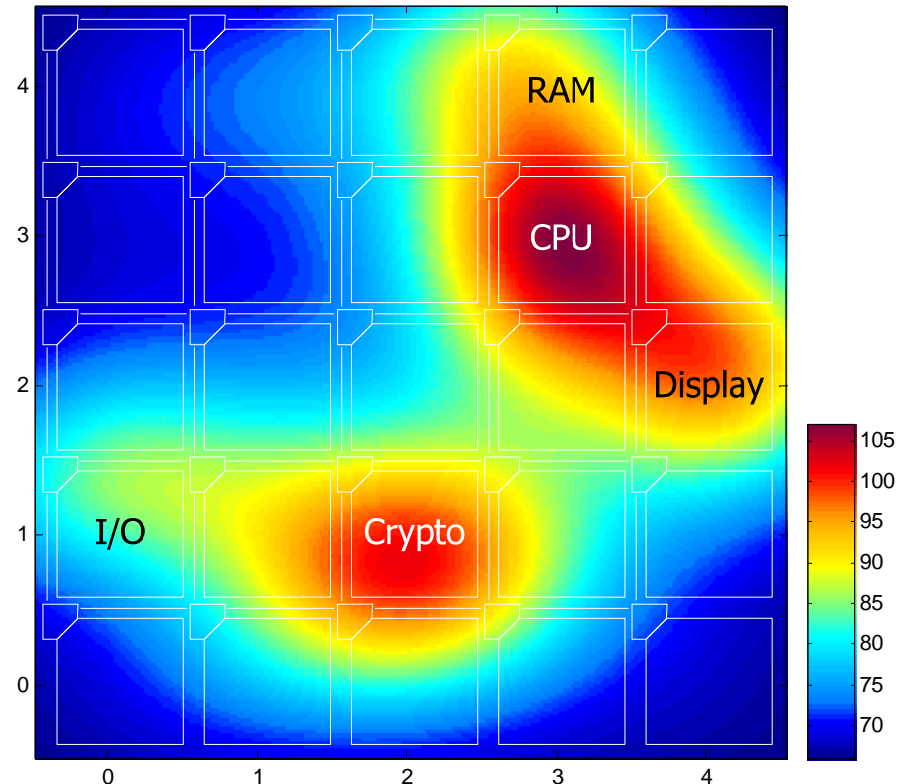


System control

Results

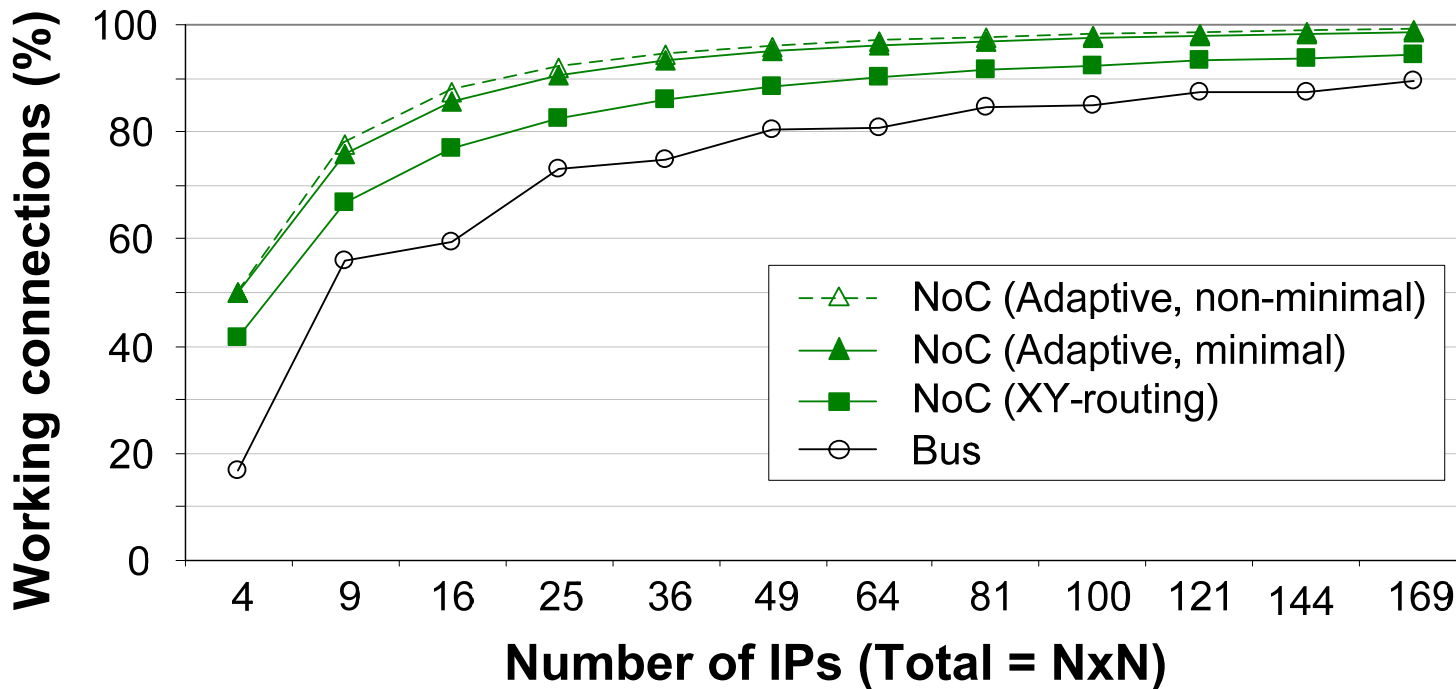
- Temperatur distribution influences
 - Performance
 - Power consumption
 - Reliability
- Dynamic power management
 - Avoid hot spots
 - Task mapping
 - Packet congestions
 - DV/FS, Clock-gating ...

Application example for the temperature distribution of a 5x5 network



Results

Reliability



- Permanent, single error
- Average number of working connections
- Cohesive connected system

Summary

- Motivation for investigating
 - Networks-on-Chip
 - Power and reliability
- Combined approach for design space exploration
- Comparison of results to a reference bus
- Consideration of dynamic behavior and control